

**CARTS USA 2011, Jacksonville, FL, March 28- 31, 2011**

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***CARTS USA 2011 Presentation***

*Power Efficiency Improvement for Low Ohm Current  
Sense Resistor*

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# Outline

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- ❑ *Motivation*
- ❑ *Review of Current Sense technique in the system*
- ❑ *Applied techniques to enhance power handling capability*
- ❑ *Result of enhance power handling capability from manufactured product test data*
- ❑ *Product improvement to prevent failure due to thermal fatigue*
- ❑ *Product specification improvement with unique construction*
- ❑ *Power efficiency improvement while detecting current with enhanced package layout technique*
- ❑ *Summary and conclusion*
- ❑ *Acknowledgement and Future work*

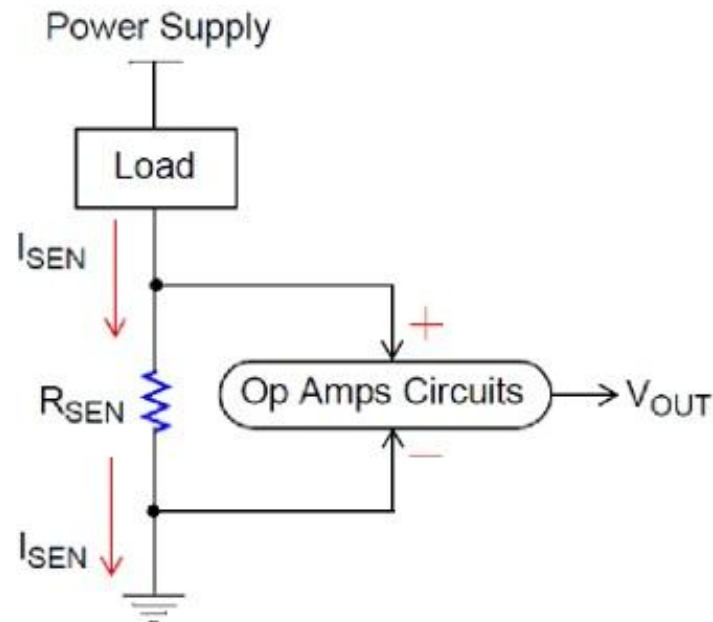
# Motivation

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- ❑ Power efficiency is becoming significantly important in present day's system design
- ❑ To minimize power loss, "Current" needs to be measured and monitored accurately throughout the system
- ❑ Typically current sense resistor is used to detect the current
- ❑ These current sense resistors need to be very low ohm value with higher rated power
- ❑ Research is done to improve power handling capability without size increment
- ❑ Increased product efficiency with unique package layout

# Review: Current Sense Technique

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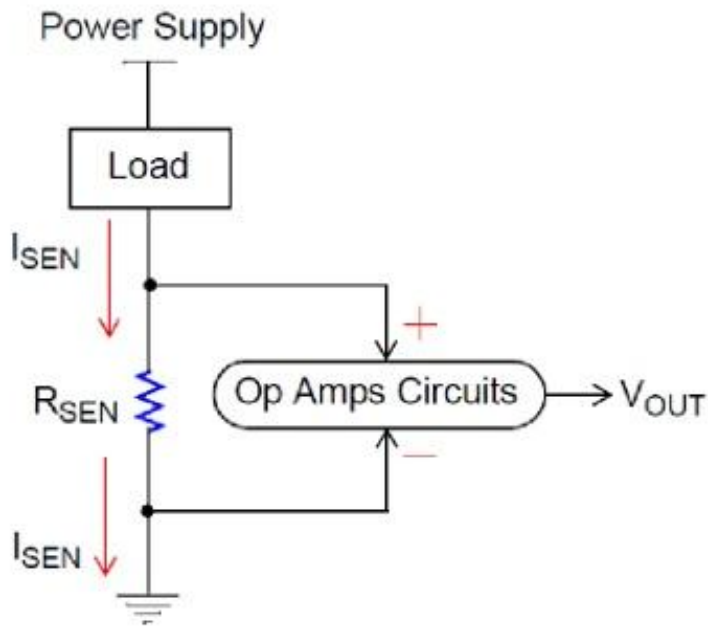


Low Side current sensing technique

- ❑ Voltage drop across  $R_{SEN}$  is amplified with Diff. Amp
- ❑  $V_{out}$  is measured as detection of Current through the Load
- ❑ From  $V_{out}$  result, applied power can be controlled for the Load

# Necessary Improvement

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Low Side current sensing technique

- ❑ Current sense resistor parameters
  - ❑ Low ohmic value
  - ❑ Enhance power handling capability
- ❑ Other resistor parameters
  - ❑ Tighter tolerance
  - ❑ Lower TCR value
  - ❑ Lower ESL value
  - ❑ Smaller size
  - ❑ Cost effective

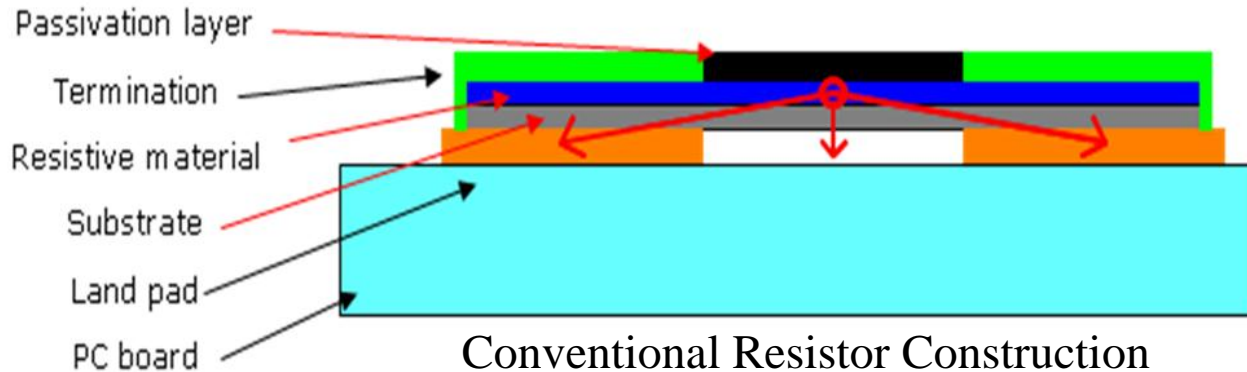
# Enhance Power Handling Capability

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- ❑ Higher applied power generate higher temperature
  - ❑ Electro migration phenomenon takes place
  - ❑ Make crack in the resistor material on the substrate
  - ❑ Resistor value goes up, Resistor opens up
  - ❑ Long time Excessive heat can cause irreversible damage to resistor product
  - ❑ Component Reliability gets significantly reduced
- ❑ Thermal Management
  - ❑ Must reduce excess heat from resistor
  - ❑ Can not let the generated heat stay in the resistive material for prolonged period of time
- ❑ Biggest challenge to enhance power handling capability is to efficiently disperse generated heat

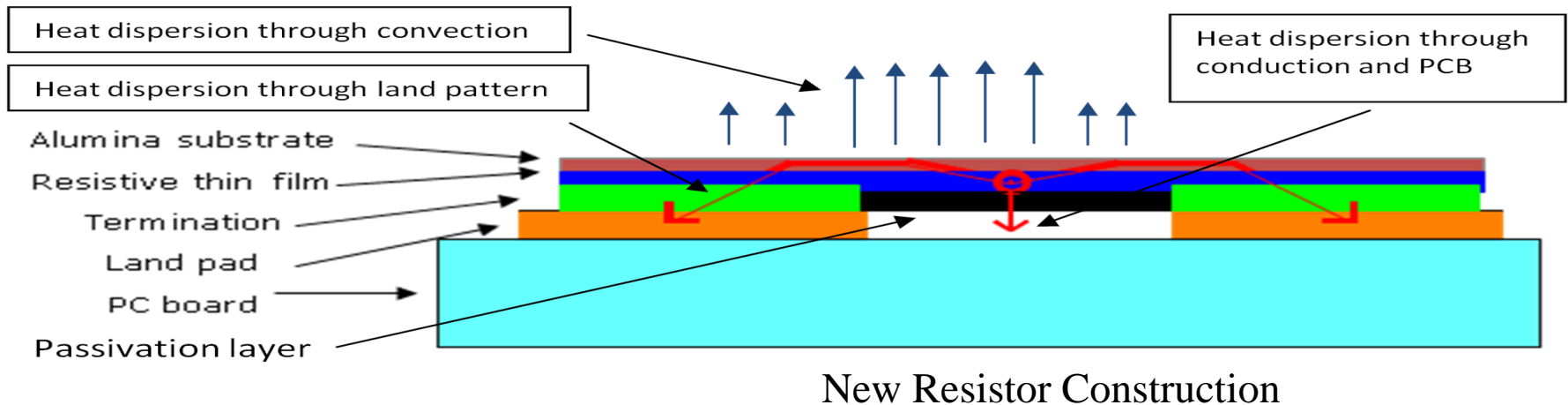
# Enhance Power Handling Capability

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- ❑ Heat Dispersion from resistor product
  - ❑ Conduction through the circuit board, ultimately by convection from circuit board
  - ❑ Through pattern then substrate then through land pad termination to circuit board
  - ❑ Gradual radiation to air through surface material and cover

# Enhance Power Handling Capability



## ❑ Improved Heat Dispersion

- ❑ Changed the construction
- ❑ Passivation is at the bottom side,
  - ❑ No direct heat transfer to the PCB
  - ❑ No heat dissipation through PCB
  - ❑ Minimizing risk of permanent thermal damage to PCB

# Enhance Power Handling Capability

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## Uniform Heat Distribution

- Resistive area as big as possible
- Eliminated one peak surface temperature
- Surface temperature is uniformly distributed
- Power specification does not need to depend on one single hot spot

## Improve Current Density

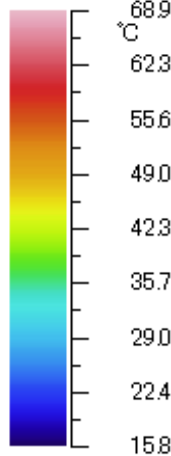
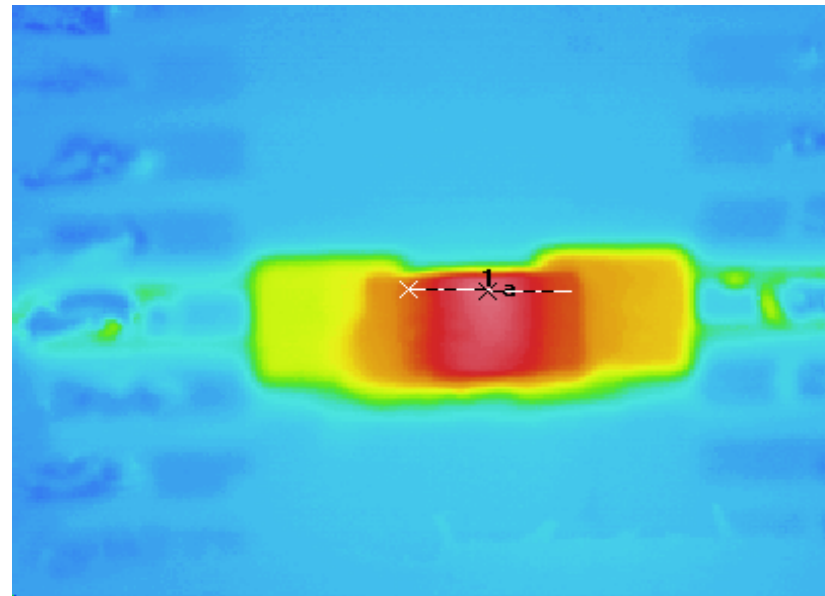
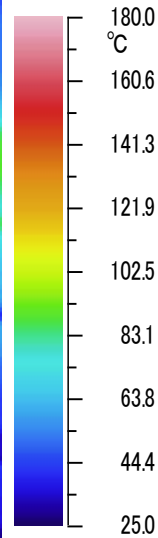
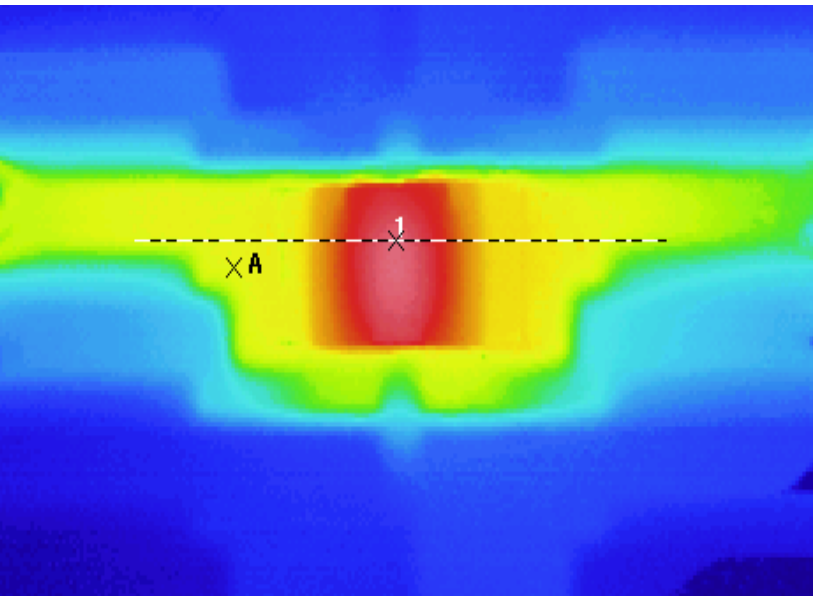
- Maximum current density – Maximum tolerated current per unit of cross sectional area
- Used NiCr as resistive material; NiCr has high current density limit
- Bigger resistive area also improves current density
- Reduced electro migration effect

# Enhance Power Handling Capability

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- ❑ Improve Heat transfer rate through Footprint
  - ❑ Lowered thermal resistance interface from resistor to circuit board
  - ❑ NiCr is deposited directly to substrate, resulting less thermal resistance between material and substrate
  - ❑ Maximized termination electrode's size
  - ❑ Used high purity, high thermal conductivity material for terminal footprint
  - ❑ Special design is considered to ensure balance distribution of generated heat
  - ❑ Improved heat transfer rate through the termination material
  - ❑ Used AlN as substrate for better thermal properties

# Thermal Profile Comparison and Result

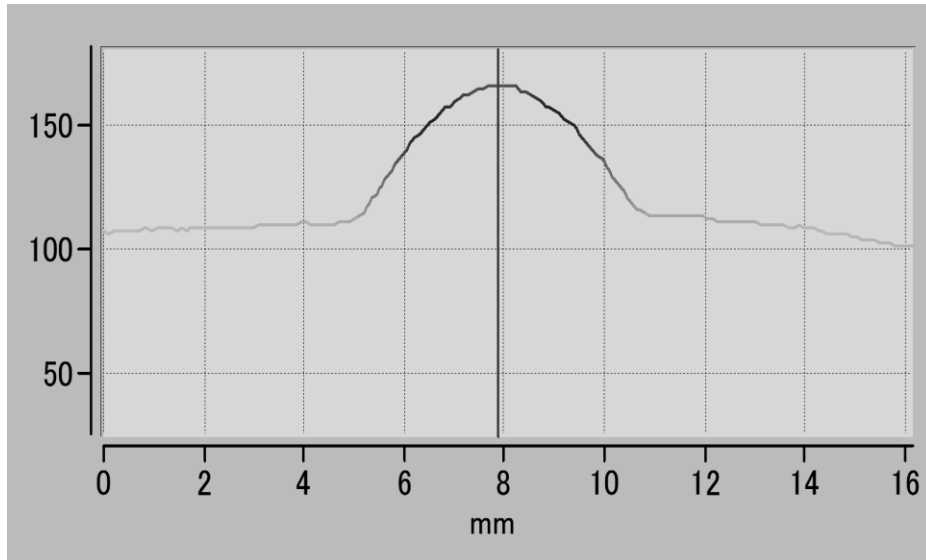


Conventional Resistor

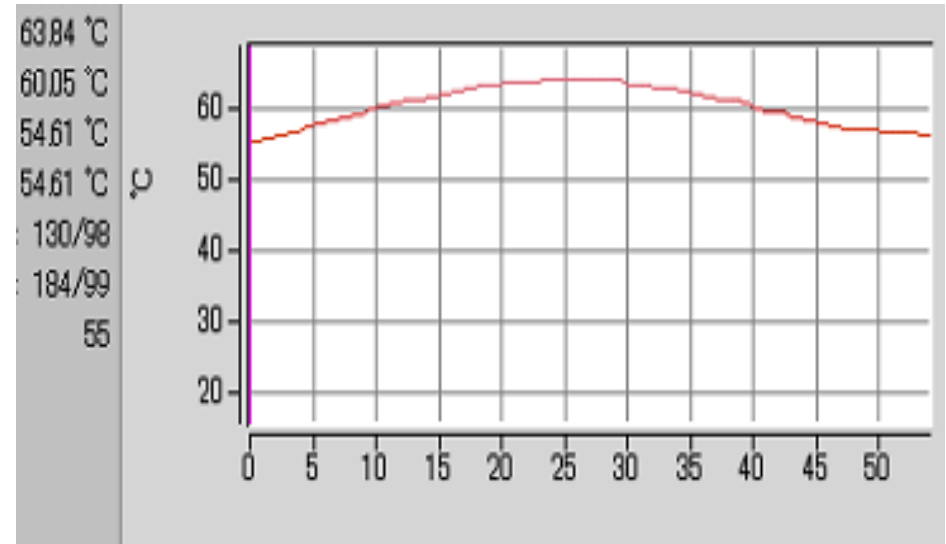
New Resistor

- ❑ Surface temperature result and thermal profile
- ❑ Condition : Power = 1Watt, Chip size = 2512, Resistor value = 3 mΩ
- ❑ Conventional Resistor Temperature: Res. = 165°C; Termination = 107°C; PCB = 75°C
- ❑ New Resistor Temperature: Res. = 65°C; Termination = 44°C; PCB = 31°C
- ❑ Thermal Resistivity : Conventional Res. = 57°C/Watt; New Res. = 19°C/Watt

# Thermal Profile Comparison and Result



Conventional Resistor



New Resistor

- ❑ Surface temperature of resistor and PCB
- ❑ Less temperature variation from resistor and PCB
- ❑ Conventional Res. = 50° C temp. difference for 4 mm distance from the resistor
- ❑ New Res. = 10° C temp. difference for 25 mm distance from the resistor

# Reduce Thermal Fatigue

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## Thermal Fatigue

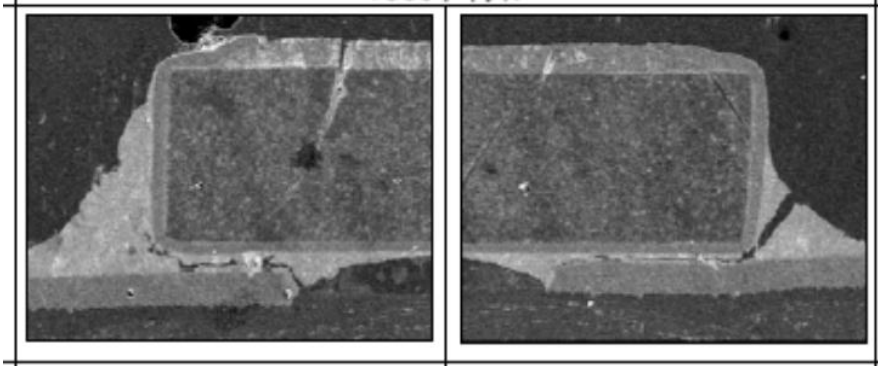
- High temperature can exceed melting point of mounting solder
- It can potentially create crack in the solder joint
  - Causes irreversible damage to resistor, Changes resistor value
  - Decreasing resistor reliability, Potential damage to PCB
- Depending on the applied power, temperature rise and fall
  - PCB and Resistor expands and contracts
  - Different expansion and contraction rate of both material can make crack in solder joint

## Reduced Thermal Fatigue

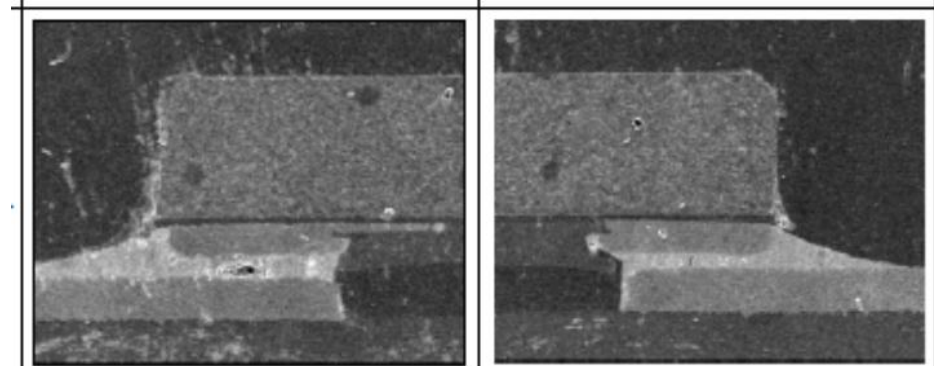
- Used termination material with similar CTE value as PCB
- Termination electrodes and PCB expands and contracts in same rate

# Reduce Thermal Fatigue

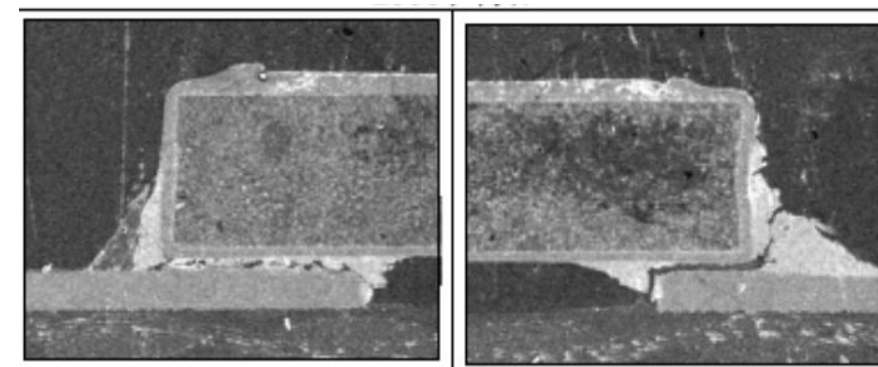
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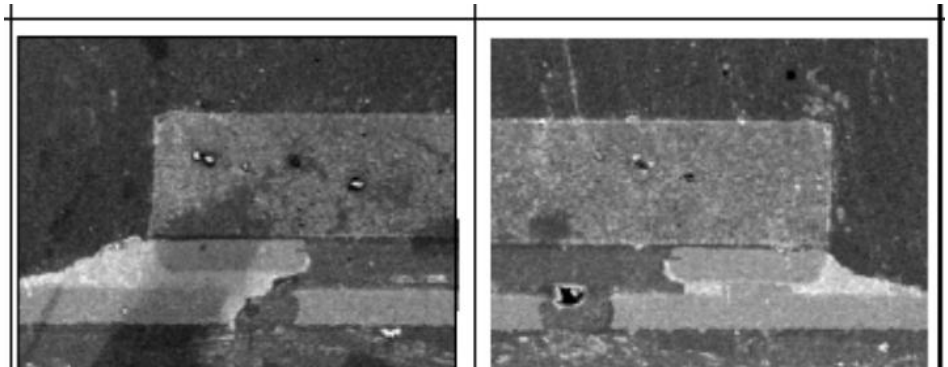
Conventional Resistor after 1000 cycle



New Resistor after 1000 cycle



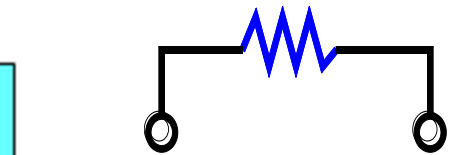
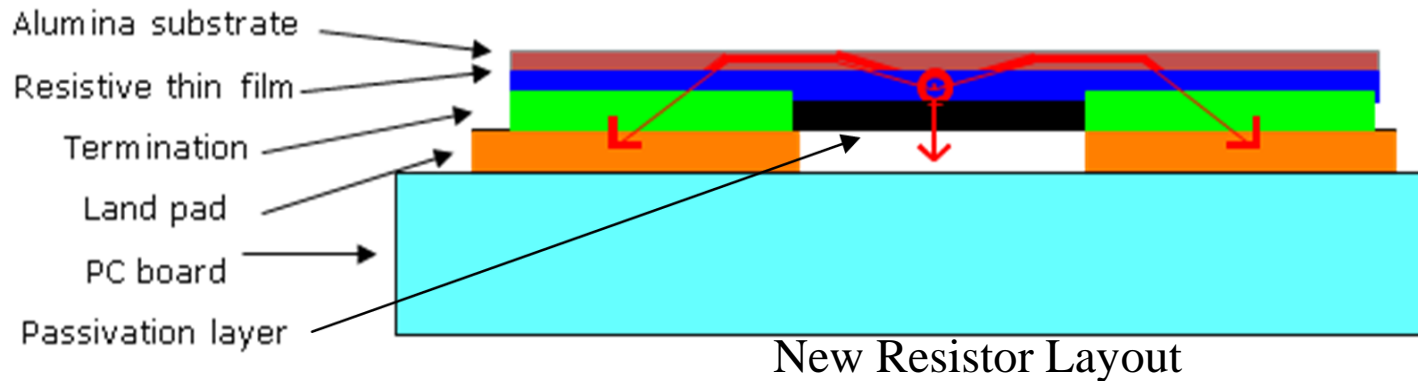
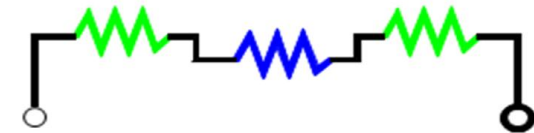
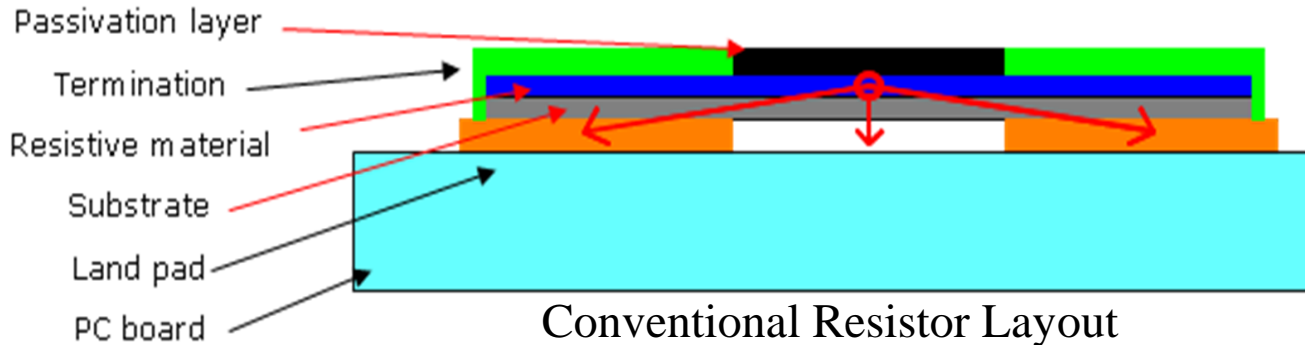
Conventional Resistor after 2000 cycle



New Resistor after 2000 cycle

- ❑ Thermal Fatigue result phenomenon comparison
- ❑ Condition = +155°C for 30 min, Room temp for 3 min, -55° for 30 min

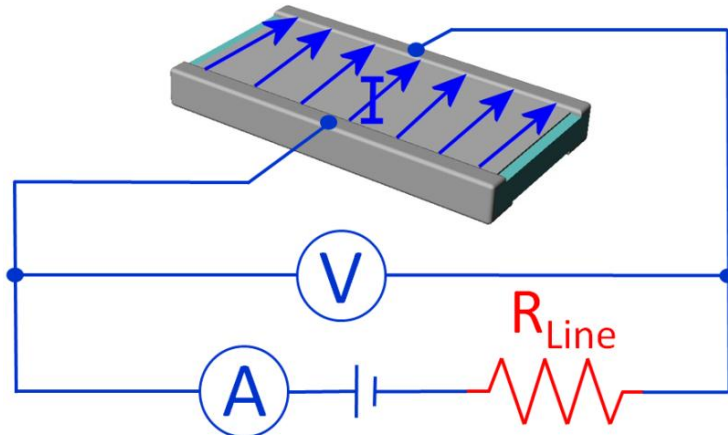
# Efficient Resistor Construction



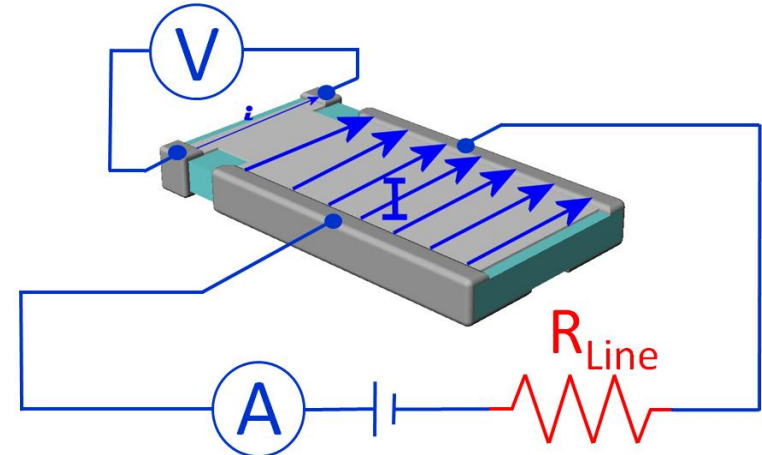
## ❑ Parallel Package Layout

- ❑ Electrode and termination laid out parallel
- ❑ Reduced contact resistance, improved tolerance level

# Power Efficiency Improvement



2 Terminal Resistor Package Schematic



4 Terminal Resistor Package Schematic

## ❑ 4 Terminal Resistor Designed

- ❑ Structure optimally for current sensing purpose
- ❑ Voltage measurement is separated from flowing current
- ❑ Improved power efficiency
- ❑ Less noise from Line Resistor

# Summary and Conclusion

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- ❑ Research was done to enhance power handling capability of low ohm current sense resistor
- ❑ Effective thermal management reduced peak surface temperature
- ❑ Thermal profile illustrated heat dispersion improvement
- ❑ Using termination material with similar CTE of PCB to prevent failure due to thermal fatigue
- ❑ Enhanced long time reliability with thermal fatigue reduction
- ❑ Reduced contact resistance by using parallel package layout
- ❑ Four terminal package layout technique was used to improve power efficiency

# Acknowledgement and Future Work

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- ❑ Future Work
  - ❑ Research work will be done on lowering resistance value
  - ❑ Power handling capability can be enhanced more
  - ❑ Enhance component tolerance value
  - ❑ Enhance TCR level
  - ❑ Size reduction
- ❑ Acknowledgement
  - ❑ We would like to thank Yokohama Denshi Seiko Co. for sharing valuable knowledge and resource

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**Thank you for your time  
and attention**